

S/N 09/834,751

FEB 11 2005

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Sergey A. Velichko et al. Examiner: Craig Steven Miller
Serial No.: 09/834,751 Group Art Unit: 2857
Filed: April 13, 2001 Docket: 303.750US1
Title: CONCURRENT CONTROL OF SEMICONDUCTOR PARAMETRIC TESTING

INFORMATION DISCLOSURE STATEMENT

MS RCE
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

In compliance with the duty imposed by 37 C.F.R. § 1.56, and in accordance with 37 C.F.R. §§ 1.97 *et. seq.*, the enclosed materials are brought to the attention of the Examiner for consideration in connection with the above-identified patent application. Applicants respectfully request that this Information Disclosure Statement be entered and the documents listed on the attached Form 1449 be considered by the Examiner and made of record. Pursuant to the provisions of MPEP 609, Applicants request that a copy of the 1449 form, initialed as being considered by the Examiner, be returned to the Applicants with the next official communication.

Pursuant to 37 C.F.R. §1.97(b), it is believed that no fee or statement is required with the Information Disclosure Statement.

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Pursuant to 37 C.F.R. 1.98(a)(2), Applicant believes that copies of cited U.S. Patents and Published Applications are no longer required to be provided to the Office. Notification of this change was provided in the United States Patent and Trademark Office OG Notices dated October 12, 2004. Thus, Applicant has not included copies of any US Patents or Published Applications cited with this submission. Should the Office require copies to be provided, Applicant respectfully requests that notice of such requirement be directed to Applicant's below-signed representative. Applicant acknowledges the requirement to submit copies of foreign patent documents and non-patent literature in accordance with 37 C.F.R. 1.98(a)(2).

The Examiner is invited to contact the Applicants' Representative at the below-listed telephone number if there are any questions regarding this communication.

Respectfully submitted,

SERGEY A. VELICHKO ET AL.

By their Representatives,

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.
P.O. Box 2938
Minneapolis, MN 55402
(612) 349-9581

Date

Feb 8 '05

By

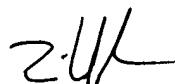

John M. Dahl
Reg. No. 44,639

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: MS Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 8 day of February, 2005.

Name

Tina Kohaut

Signature



Substitute for form 1449A/PTO
**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**
(Use as many sheets as necessary)

Complete if Known

Application Number	09/834,751
Filing Date	April 13, 2001
First Named Inventor	Velichko, Sergey
Group Art Unit	2857
Examiner Name	Miller, Craig

Sheet 1 of 1

Attorney Docket No: 303.750US1



US PATENT DOCUMENTS

Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Filing Date If Appropriate
	US-2002/0121915 A1	09/05/2002	Alonso Montull, J. I., et al.	03/05/2001
	US-2003/0200513 A1	10/23/2003	Bergman Reuter, B. L., et al.	04/23/2002
	US-2003/0212469 A1	11/13/2003	Wang, S , et al.	03/17/2003
	US-2004/0153979 A1	08/05/2004	Chang, F.	01/30/2003
	US-2004/0210413 A1	10/21/2004	Dorough, M. J., et al.	04/17/2003
	US-5,059,899	10/22/1991	Farnworth, W. D., et al.	08/16/1990
	US-6,785,413	08/31/2004	Barcomb, K. J., et al.	08/24/1999

EXAMINER

DATE CONSIDERED

Substitute Disclosure Statement Form (PTO-1449)

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional) 2 Applicant is to place a check mark here if English language Translation is attached

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Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Applicants would like to bring to the Examiner's attention the following related application(s) in the above-identified patent application:

<u>Serial/Patent No.</u>	<u>Filing Date</u>	<u>Attorney Docket</u>	<u>Title</u>
10/924695	August 24, 2004	303.821US2	DYNAMICALLY ADAPTABLE SEMICONDUCTOR PARAMETRIC TESTING

Respectfully submitted,

SERGEY A. VELICHKO ET AL.

By Applicants' Representatives,

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Date Feb 8 '05

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John M. Dahl
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Name

Tina Kishab

Signature

